- Single-Chip Interface Solution for the 9-Pin **GeoPort™ Peripheral Data Circuit-**Terminating Equipment (DCE) for the **Intelligent Network Port**
- Designed to Operate up to 4-Mbits/s Full **Duplex**
- Single 5-V Supply Operation
- 10-kV ESD Protection on Bus Terminals
- Backward Compatible with AppleTalk™ and LocalTalk™ LANs
- **Combines Multiple Components into a Single Chip Solution**
- Complements the SN75LBC776 9-Terminal **GeoPort Host Data Terminal Equipment** (DTE) Interface Device
- **LinBiCMOS™ Process Technology**

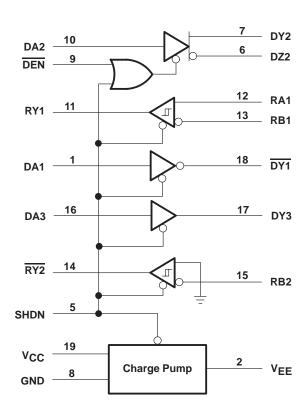
description

The SN75LBC777 is a low-power LinBiCMOS device that incorporate the drivers and receivers for a 9-pin GeoPort peripheral interface. GeoPort combines hybrid EIA/TIA-422-B and EIA/ TIA-423-B drivers and receivers to transmit data up to four-Mbit/s full duplex. GeoPort is a serial communications standard that is intended to replace the RS-232, AppleTalk, and printer ports all in one connector in addition to providing real-time data transfer capability. SN75LBC777 provides point-to-point connections between GeoPort-compatible devices with data transmission rates up to 4-Mbit/s full duplex over a 4-foot cable. Applications include connection to telephone, integrated services digital network (ISDN), digital sound and imaging, fax-data modems, and other traditional serial and parallel connections. The GeoPort is backwardly compatible to both LocalTalk and AppleTalk LANs.

While the SN75LBC777 is powered off $(V_{CC} = 0)$ the outputs are in a high-impedance state. When the shutdown (SHDN) terminal is high, the charge pump is powered down and the outputs are in a high-impedance state. When high, the driver enable (DEN) terminal puts the outputs of the differential driver into a high-impedance state.

DW PACKAGE (TOP VIEW) 10 DA1 □ 20 ☐ GND 2 19 V_{CC} $V_{EE} \square$ C- \Box 3 18 DY1 4 17 C+ 🗆 ☐ DY3 SHDN I 5 16 □ DA3 DZ2 6 15 RB2 7 DY2 \square 14 □ RY2 8 13 GND □ ☐ RB1 9 DEN \square 12 □ RA1 DA2 [10 11

logic diagram (positive logic)





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description (continued)

A switched-capacitor voltage converter generates the negative voltage required from a single 5-V supply using two $0.33-\mu F$ capacitors. One capacitor is between the C+ and C- terminals and the other is between V_{EE} and ground.

The SN75LBC777 is characterized for operation over the 0°C to 70°C temperature range.

DRIVER FUNCTION TABLE

	INPUTS			ENABLE		OUTPUTS				
DA1	DA2	DA3	SHDN	DEN	DY1	DY2	DZ2	DY3		
Н	Х	Н	L	Х	L	Х	Х	Н		
L	X	L	L	X	Н	Х	Χ	L		
X	Н	X	L	L	Х	Н	L	Х		
X	L	X	L	L	Х	L	Н	Х		
OPEN	OPEN	OPEN	L	L	L	Н	L	Н		
X	X	X	Н	Χ	Z	Z	Z	z		
X	X	X	Х	Н	Х	Z	Z	Х		
Х	Χ	Χ	OPEN	OPEN	Z	Z	Z	Z		

H = high level, L= low level, X = irrelevant, ? = indeterminate, Z = high impedance (off)

RECEIVER FUNCTION TABLE

	INPUT	S	ENABLE	OUT	PUTS
RA1	RB1	RB2	SHDN	RY1	RY2
Н	L	Н	L	Н	L
L	Н	L	L	L	Н
OP	PEN	OPEN	L	Н	Н
SHC	PRT [†]	SHORT†	L	?	?
Х	Χ	Х	Н	Z	Z
Χ	Х	Х	OPEN	Z	Z

 $^{\dagger}-0.2~V < V_{\mbox{\scriptsize ID}} < 0.2~V$ H = high level, L= low level, X = irrelevant, ? = indeterminate,



Z = high impedance (off)

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Positive supply voltage range, V _{CC} (see Note 1)	0.5 to 7 V
Negative supply voltage range, V _{EE} (see Note 1)	
Receiver input voltage range (RA1, RB1, RB2)	
Receiver differential input voltage range, V _{ID}	
Receiver output voltage range (RY1, RY2)	
Driver output voltage range (Power Off)(DY1, DY2, DZ2, DY3)	
Driver output voltage range (Power On)(DY1, DY2, DZ2, DY3)	
Driver input voltage range (DA, SHDN, DEN)	
Electrostatic discharge (see Note 2)	
Bus Pins (Class 3 A)	10 kV
Bus Pins (Class 3 B)	600 V
All Pins (Class 3, A)	
All Pins (Class 3 B)	200 V
Continuous total power dissipation	See Dissipation Rating Table
Operating free-air temperature range, T _A	0°C to 70°C
Storage temperature range, T _{stq}	65°C to 150 °C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltages values are with respect to the network ground terminal unless otherwise noted.

2. This rating is measured using MIL-STD-883C Method, 3015.7.

DISSIPATION RATING TABLE

PACKAGE	$T_{\mbox{\scriptsize A}} \leq 25^{\circ}\mbox{\scriptsize C}$ POWER RATING	DERATE FACTOR ABOVE T _A = 25°C	T _A = 70°C POWER RATING
DW	1125 mW	9.0°C	720 mW



recommended operating conditions

	MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}	4.75	5	5.25	V
High-level input voltage, V _{IH} (DA, SHDN, DEN)	2		5.25	V
Low-level input voltage, V _{IL} (DA, SHDN, DEN)			0.8	V
Receiver common-mode input voltage, V _{IC}	-7		7	V
Receiver differential input voltage, V _{ID}	-12		12	V
Voltage converter filter capacitance	0.33			μF
Voltage converter filter capacitor equivalent series resistance (ESR)	0		0.2	Ω
Operating free-air temperature, T _A			70	°C

driver electrical characteristics over operating free-air temperature range (unless otherwise noted)

	PARAMETER		TEST CON	DITIONS	MIN	TYP	MAX	UNIT
V	High-level output voltage		R _L = 12 kΩ		3.6	4.5		V
VOH	High-level output voltage	Single ended,	R _L = 120 Ω		2	3.6		V
Voi	Low-level output voltage	See Figure 1	R _L = 12 kΩ			-4.5	-3.6	V
VOL	Low-level output voltage		R _L = 120 Ω			-2.7	-1.8	V
IVODI	Magnitude of differential output	t voltage	R _L = 120 Ω,	See Figure 2	4			V
Δ V _{OD}	Change in differential voltage	magnitude					250	mV
Voc	Common-mode output voltage				-1		3	V
ΔV _{OC} (SS)	Magnitude of change, common state output voltage	n-mode steady-	See Figure 3				200	mV
ΔVOC(PP)	Magnitude of change, common peak-to-peak output voltage	n-mode				700		mV
1	Cumply ourrent		SHDN = $\overline{\text{DEN}}$ = 0 V,	No Load		7	15	mA
Icc	Supply current SHDN = DEN = 5 V, No Load		No Load			100	μΑ	
loz	High-impedance output curren	t	$V_{CC} = 0 \text{ or } 5 \text{ V},$	$-10 \le V_O \le 10 \text{ V}$			±100	μΑ
IOS	Short-circuit output current		V _{CC} = 5.25 V, See Note 3	$-5 \text{ V} \leq \text{V}_{\text{O}} \leq 5 \text{ V},$		±170	±450	mA

NOTE 3: Not more than one output should be shorted at one time.



driver switching characteristics over recommended operating conditions (unless otherwise noted)

	PARAMETER		TEST CONDITIONS	MIN	TYP	MAX	UNIT
tPHL	Propagation delay time, high-to-low level output				40	75	ns
tPLH	Propagation delay time, low-to-high level output				40	75	ns
t _{PZL}	Driver output enable time to low-level output	SHDN			25	100	μs
^t PZH	Driver output enable time to high-level output	SHDN	Single-ended,		25	100	μs
tPLZ	Driver output disable time from low-level output	SHDN	$R_L = 120 \Omega$, See Figure 4		30	100	ns
tPHZ	Driver output disable time from high-level output	SHDN			30	100	ns
t _r	Rise time			10	25	75	ns
t _f	Fall time			10	25	75	ns
tPHL	Propagation delay time, high-to-low level output				40	75	ns
tPLH	Propagation delay time, low-to-high level output				40	75	ns
	Driver output enable time to low-level output	SHDN			25	100	μs
^t PZL		DEN			35	100	ns
	Driver output enable time to high-level output	SHDN			25	100	μs
^t PZH	Driver output eriable time to nigri-level output	DEN	Differential,		35	150	ns
	Driver output disable time from low level output	SHDN	$R_L = 120 \Omega$, See Figure 5		30	100	ns
^t PLZ	Driver output disable time from low-level output	DEN			30	100	ns
	Driver output disable time from high-level output	SHDN			35	100	ns
^t PHZ	Driver output disable time from high-level output	DEN]		35	100	ns
t _r	Rise time]	10	25	75	ns
t _f	Fall time] i	10	25	75	ns
tSK(P)	Pulse skew, tpLH - tpHL					22	ns

receiver electrical characteristics over free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CO	NDITIONS	MIN	TYP	MAX	UNIT
V _{IT+}	Positive-going input threshold voltage					200	mV
V _{IT} _	Negative-going input threshold voltage	1		-200			mV
V _{hys}	Differential input voltage hysteresis (V _{IT+} – V _{IT-})]			50		mV
Vон	High-level output voltage (see Note 4)	$I_{OH} = 2 \text{ mA},$	VIC = 0	2	4.9		V
VOL	Low-level output voltage	$I_{OL} = -2 \text{ mA},$	VIC = 0		0.2	0.8	V
100	Chart aircuit autaut aureant	VO = 0		-85	-45		mA
los	Short-circuit output current	V _O = 5.25 V	·		45	85	mA
R _I	Input resistance	$V_{CC} = 0 \text{ or } 5.25 \text{ V},$	-12 V ≤ V _I ≤ 12 V	6	30		kΩ

NOTE 4: If the inputs are left unconnected, RA1 interprets this as a high-level input and RB1 and RB2 interpret this as a low-level input so that all outputs are at the high level.

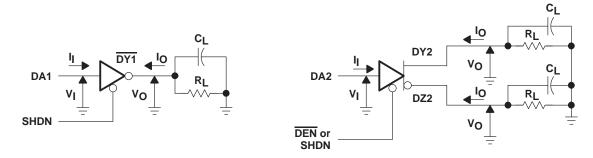


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receiver switching characteristics over free-air temperature range (unless otherwise noted)

	PARAMETER	TEST CO	NDITIONS	MIN	TYP	MAX	UNIT
tPHL	Propagation delay time, high-to-low level output				30	75	ns
tPLH	Propagation delay time, low-to-high level output]			30	75	ns
t _r	Rise time	$R_L = 2 k\Omega$, See Figure 6	$C_L = 15 pF$,		15	30	ns
t _f	Fall time				15	30	ns
tsk(p)	Pulse skew tpLH-tpHL					20	ns
tPZL	Receiver output enable time to low-level output				35	100	ns
^t PZH	Receiver output enable time to high-level output	Differential,	$C_{L} = 50 \text{ pF},$		35	100	ns
tPLZ	Receiver output disable time from low-level output	See Figure 7			21	100	ns
t _{PHZ}	Receiver output disable time from high-level output]			21	100	ns
tPZL	Receiver output enable time to low-level output				12	25	μs
tPZH	Receiver output enable time to high-level output	Single-ended,	C _L = 50 pF,		12	25	μs
tPLZ	Receiver output disable time from low-level output	See Figure 7	_ , ,		25	100	ns
tPHZ	Receiver output disable time from high-level output				125	400	ns



TEST CIRCUIT

NOTES: A. $C_L = 50 pF$

B. Driver 3 is a noninverting version of driver 1.

Figure 1. Single-Ended Driver DC Parameter Test Circuits

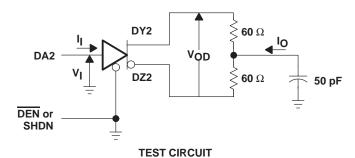
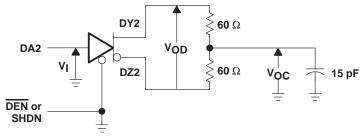
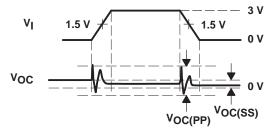


Figure 2. Differential Driver DC Parameter Test Circuit



TEST CIRCUIT (see Note A)

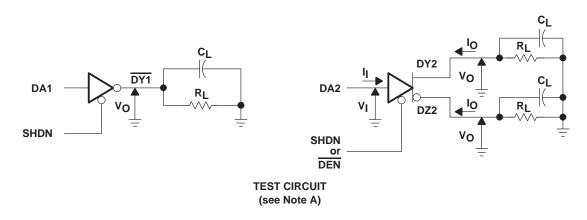


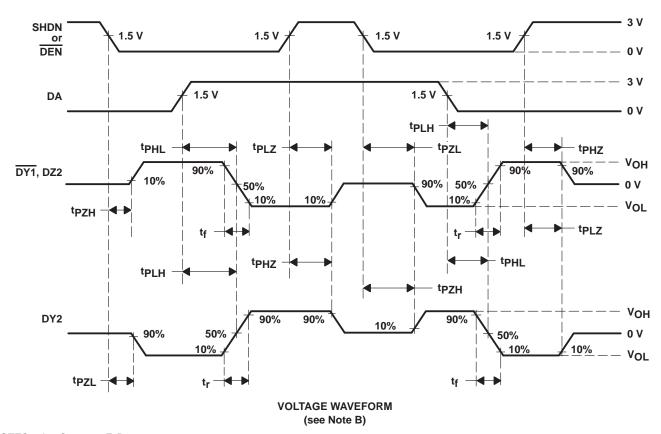
VOLTAGE WAVEFORM

NOTE A. Measured 3dB Bandwidth = 300 MHz

Figure 3. Differential Driver Common-Mode Output Voltage Test Circuit and Waveform







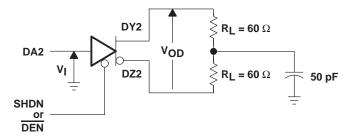
NOTES: A. $C_L = 50 \text{ pF}$, $R_L = 120 \Omega$

B. The input waveform t_f , $t_f \le 10$ ns.

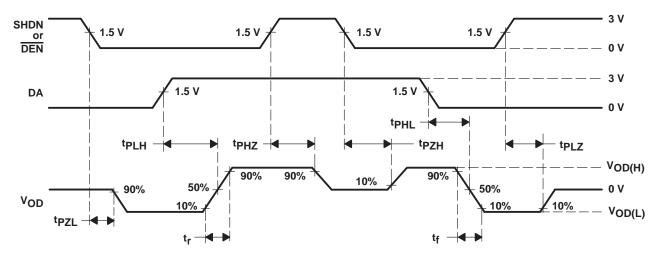
C. Driver 3 is a noninverting version of driver 1.

Figure 4. Single-Ended Driver Propagation and Transition Times Test Circuits and Waveform





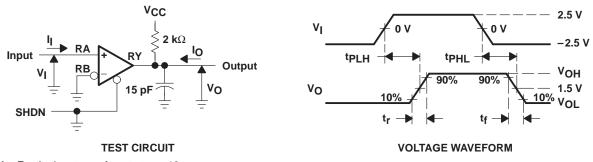
TEST CIRCUIT



VOLTAGE WAVEFORM

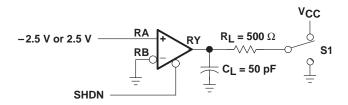
NOTE A: For the input waveform $t_{\mbox{\scriptsize f}},\,t_{\mbox{\scriptsize f}}<$ = 10 ns

Figure 5. Differential Driver Propagation and Transition Times Test Circuit and Waveforms

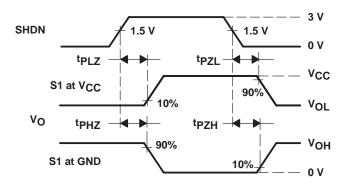


NOTE A: For the input waveform t_{f} , $t_{f} < = 10 \text{ ns}$

Figure 6. Receiver Propagation and Transition Times Test Circuit and Waveform



TEST CIRCUIT

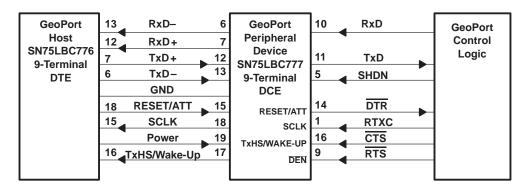


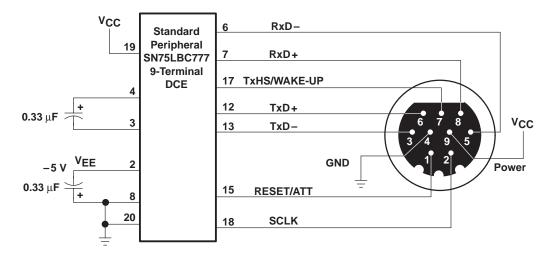
VOLTAGE WAVEFORM

NOTE A: For the input waveform t_r , $t_f < = 10 \text{ ns}$

Figure 7. Receiver Enable and Disable Test Circuit and Waveforms

APPLICATION INFORMATION





NOTE A: A potential charge pump capacitor is the AVX 0805YC334MATXA or an equivalent.

Figure 8. GeoPort 9-terminal DCE Connection Application

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generator characteristics

	PARAMETER	TEST C	CONDITIONS	232/	232/V.28		423/V.10		562	
	PARAMETER	TEST	TEST CONDITIONS		MAX	MIN	MAX	MIN	MAX	UNIT
		Open circuit			25	4	6		13.2	V
IVOI	Output voltage magnitude	$3 \text{ k}\Omega \leq \text{RL} \leq 7$	7 kΩ	5	15	N/	4	3.7		V
		$R_L = 450 \Omega$	R _L = 450 Ω		4	3.6		N/	4	V
los	Short-circuit output current	V _O = 0			100		150		60	mA
R _O (OFF)	Power-off source resistance	$V_{CC} = 0$,	V _O < 2 V	300		N/	A	300		Ω
IO(OFF)	Power-off output current	$V_{CC} = 0$,	V _O < 6 V	N/	А		±100	N/	4	μΑ
SR	Output voltage slew rate				30	N/	A	4	30	V/μs
		±3.3 V to ±3.3	3 V	N/	4	N/	A	0.22	2.1	μs
t _t	Output transition time	±3 V to ±3 V			0.04	N/	A	N/	4	ui†
		10% to 90%		N/	4		0.3	N/	4	ui†
VO(RING)	Output voltage ringing		·	N/	4		10%		5%	

 $[\]dagger$ ui is the unit interval and is the inverse of the signaling rate (a.k.a. bit time).

receiver characteristics

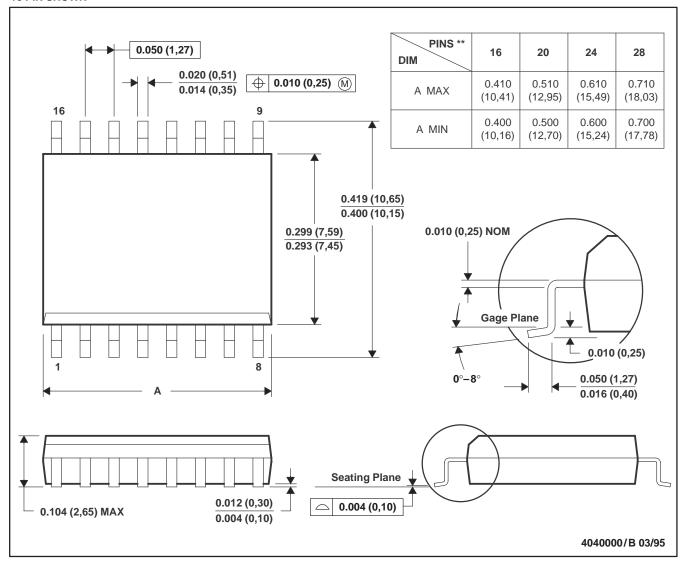
	PARAMETER	TEST CONDITIONS	232/V.28		423/V.10		562		UNIT
PARAMETER		TEST CONDITIONS	MIN	MAX	MIN	MAX	MIN	MAX	UNIT
$ V_I $	Input voltage			25		10		25	V
.,	Input voltage threshold	V _I < 15 V	-3	3	N/	4	-3	3	V
VIT	Input voltage threshold	V _I < 10 V	N/	Ą	-0.2	0.2	N/	4	V
Rį	Input registance	3 V < V _I < 15 V	3	7	N/	4	3	7	kΩ
	Input resistance	V _I < 10 V	N/	4	4	·	N/	4	kΩ

MECHANICAL INFORMATION

DW (R-PDSO-G**)

PLASTIC SMALL-OUTLINE PACKAGE

16 PIN SHOWN



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-013

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